

# Non-destructive eddy current inspection of highly conductive thin layer deposits via asymptotic models

Zixian JIANG, CMAP

Highly conductive thin layer deposits may blind the eddy current probes in non-destructive inspections. In this talk, we study several asymptotic models using different rescaling techniques to represent the thin layer by some transmission conditions on an interface. We choose a pertinent model from which we develop the inversion methods to reconstruct the layer thickness using eddy current signals. We give some numerical examples showing the modeling and the identification of thin layers.

## Références